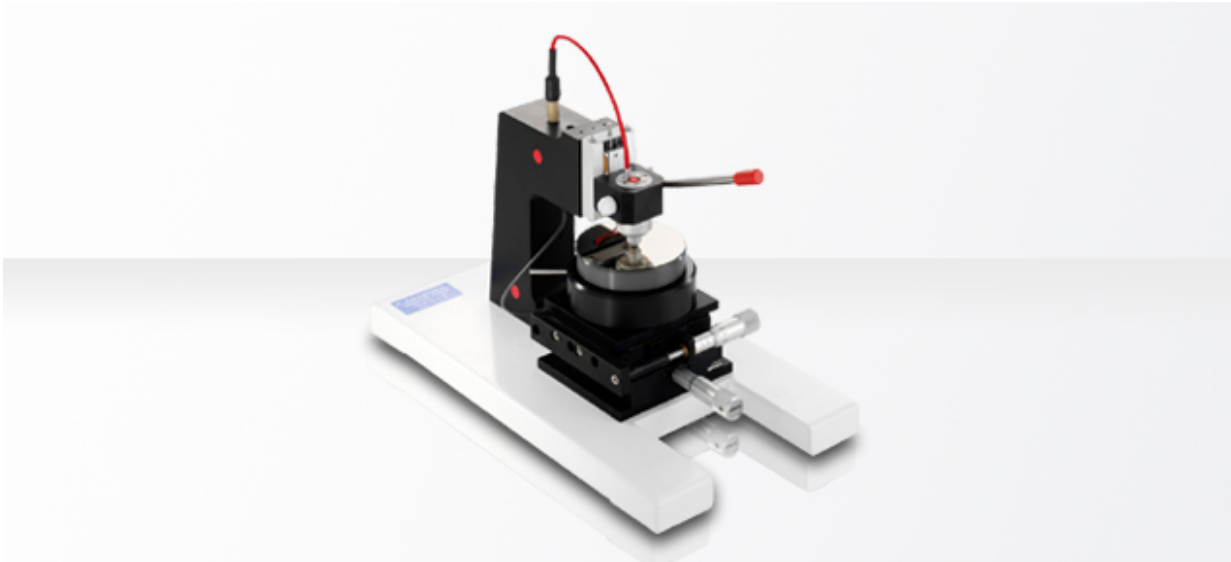


Multiheight Microposition Probe Stand

 **JANDEL**



Jandel Engineering Limited offers the Multiheight Probe stand with micrometer controlled X-Y stage as a solution for measurements on sample sizes from several mm square up to 300mm. The X-Y microposition table can be easily added when measurement of small samples is desired. With only four screws to undo it is easily removed, so that large samples up to 300mm diameter or ingots up to 250mm high can be accommodated (thicker samples can be accommodated on request).

Multiheight Microposition Probe Stand

Max. sample size	Samples up to 250mm diameter (300mm option at no extra cost)
Max. sample thickness	Samples up to 250mm high can be measured (higher on request)
Microswitch	Prevents current flow when probe is not in contact with the sample
Manual Control	Simple lever operation for probe contact and removal
Simple set up	Single wire connects the probe stand and electronics
X-Y Stage	Offers micrometer controlled manipulation of small samples
Automation	Optional automated z-motion is available

System Configuration

Component parts:

- A. Measurement Base - 1pc
- B. Multiheight assembly - 1pc
- C. Multiheight Column - 1pc
- D. Four point probe head - 1pc
- E. Connecting cable - 1pc
- F. Micrometer table - 1pc

System Footprint

- A. Multiheight Base: 250mm W x 290mm L x 8mm H (320mm x 370mm x 8mm option)
- B. Multiheight Probe assembly: 60mm W x 280mm L x 80mm H (60mm x 330mm x 80mm option)

Type	Tip	Forc	Spacing
A	40u	100g	1mm
B	100u	100g	1mm
C	200u	100g	1mm
D	500u	70g	1mm
E	40u	200g	1.591mm
F	40u	100g	0.635mm
G	100u	100g	0.635mm
H	200u	100g	0.635mm

Type A-D and F-H are user adjustable in the range 60g-150g and supplied at value shown

